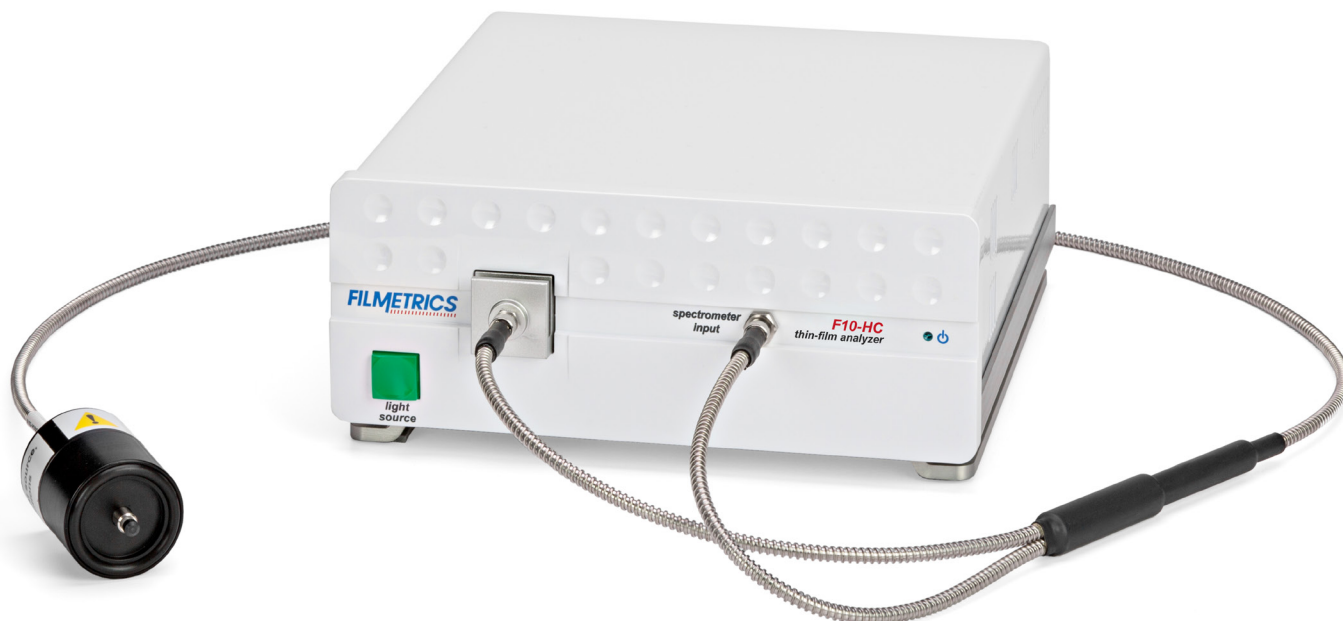


F10-HC

Thin-Film Analyzer



An Advanced Thin-Film Measurement System at an Affordable Price

The F10-HC is based on the Filmetrics F20 platform where analysis of spectral reflectance data provides film measurement results quickly. Plus, the advanced simulation algorithms in the F10-HC software are specifically designed to measure single and multiple layers (e.g., primer/hardcoat) encountered in thick film applications.

Unprecedented Ease of Use

The F10-HC is now even easier to use with the new Template Mode feature. This option allows the user to import an image of the sample (see reverse) and define measurement points directly on the image. The user is automatically notified of whether or not a measurement is valid, and the results are displayed on the image.

No Routine Reference Required

The F10-HC can now perform an automatic baseline procedure as well as set its own integration time. These innovations allow the user to start making measurements instantly, without the need to perform frequent baseline measurements.

Backside Reflection

Backside reflections can make thickness measurement a challenge for optical techniques. With the F10-HC system's unique contact probe, the effect of backside reflections are minimized so the user can measure coatings with a higher degree of accuracy and confidence in the results.

The Filmetrics Advantage

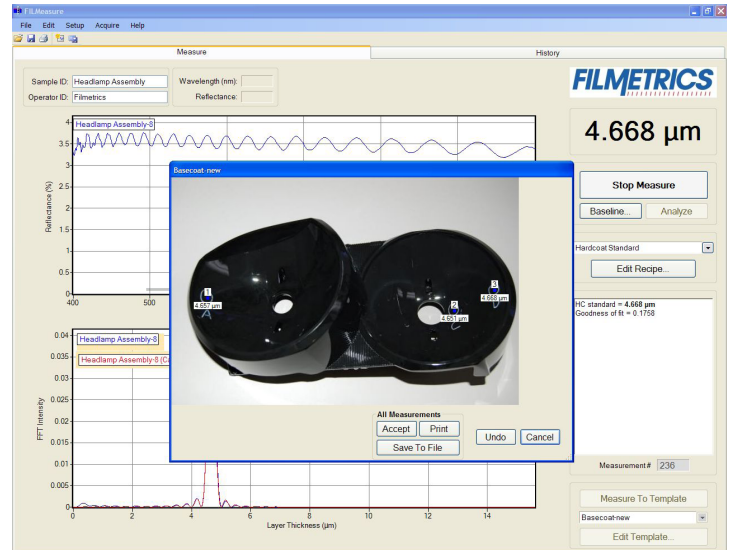
- World's leader in tabletop thin-film measurement
- 24-hour phone, e-mail, and online support
- Intuitive analysis software standard with every system

Additional Features

- Built-in online diagnostics
- Standalone analysis software included
- Sophisticated history function for saving, reproducing, and plotting results

F10-HC

Thin-Film Analyzer



The user can import an image of the sample into the software and define measurement points.

Thickness

Measurement Range:	0.05-70 µm
Accuracy*:	Greater of 0.2% or 0.01 µm
Precision*:	0.001 µm
Stability*:	0.001 µm

Spectrometer

Wavelength Range:	380-1050 nm
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* Spectrum matching mode, material dependent.

General

Probe Spot Size:	200 µm
Light Source:	Internal, Halogen
Power Requirements:	100-240 VAC, 50-60 Hz, 0.3-0.1 A

Computer Requirements

Processor Clock Speed:	1 GHz min
Interface:	USB 1.0 (2.0 recommended)

Operating System

PC:	Windows XP (SP2) - Latest Windows (64-bit)
Mac:	OS X Lion - Latest Mac OS running Parallels



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